Application/Control No. 08/879,467 Examiner Wenpeng Chen Applicant(s)/Patent Under Reexamination DURBIN ET AL. Art Unit Page 1 of 1

Notice of References Cited

U.S. PATENT DOCUMENTS

	U.S. FATENT DOCUMENTS							
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	Α	US-						
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	С	US-						
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	G	US-						
	Н	US-						
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	J	US-						
	κ	US-						
	L	US-						
	М	US-						

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 02235188 A	09-1990	Japan	TAMURA et al.	G06K 07/10
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NON-PATENT DOCUMENTS

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